### 30V DUAL N AND P-CHANNEL ENHANCEMENT MODE MOSFET

### **SUMMARY**

N-CHANNEL:  $V_{(BR)DSS}$ =30V;  $R_{DS(ON)}$ =0.135 $\Omega$ ;  $I_D$ =2.3A P-CHANNEL:  $V_{(BR)DSS}$ =-30V;  $R_{DS(ON)}$ =0.185 $\Omega$ ;  $I_D$ =-2.0A

### **DESCRIPTION**

This new generation of high density MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.



#### **FEATURES**

- Low on-resistance
- · Fast switching speed
- · Low threshold
- Low gate drive
- Low profile SOIC package

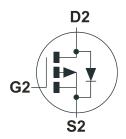
### **APPLICATIONS**

- DC DC converters
- Power management functions
- Disconnect switches
- Motor control

# G1 S1

**N-channel** 

**D1** 

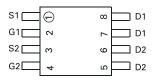


P-channel

### **ORDERING INFORMATION**

DEVICE	REEL SIZE (inches)	TAPE WIDTH (mm)	QUANTITY PER REEL
ZXMD63C03XTA	7	12 embossed	1,000
ZXMD63C03XTC	13	12 embossed	4,000

### Pin-out



Top view

### **DEVICE MARKING**

ZXM63C03



### **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	N-CHANNEL	P-CHANNEL	UNIT
Drain-Source Voltage	V <sub>DSS</sub>	30	-30	V
Gate- Source Voltage	V <sub>GS</sub>	±	±20	
Continuous Drain Current $(V_{GS}=4.5V; T_A=25^{\circ}C)(b)(d)$ $(V_{GS}=4.5V; T_A=70^{\circ}C)(b)(d)$	I <sub>D</sub>	2.3 1.8	-2.0 -1.6	A A
Pulsed Drain Current (c)(d)	I <sub>DM</sub>	14	-9.6	А
Continuous Source Current (Body Diode)(b)(d)	Is	1.5	-1.4	А
Pulsed Source Current (Body Diode)(c)(d)	I <sub>SM</sub>	14	-9.6	А
Power Dissipation at T <sub>A</sub> =25°C (a)(d) Linear Derating Factor	P <sub>D</sub>		87 .9	W mW/°C
Power Dissipation at T <sub>A</sub> =25°C (a)(e) Linear Derating Factor	P <sub>D</sub>	1.04 8.3		W mW/°C
Power Dissipation at T <sub>A</sub> =25°C (b)(d) Linear Derating Factor	P <sub>D</sub>	1.25 10		W mW/°C
Operating and Storage Temperature Range	T <sub>j</sub> :T <sub>stg</sub>	-55 to	+150	°C

### THERMAL RESISTANCE

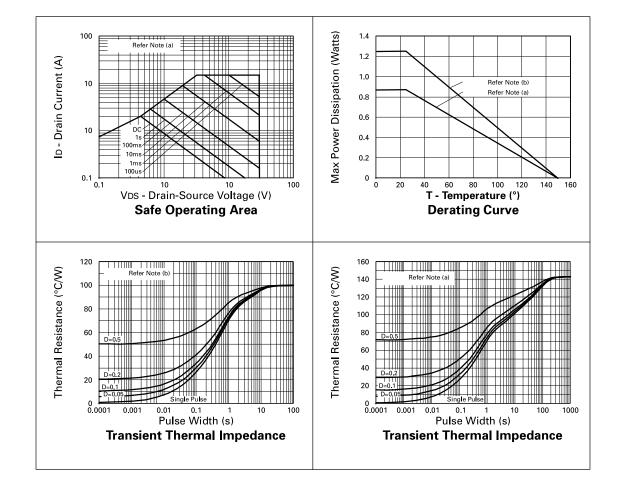
PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)(d)	$R_{\theta JA}$	143	°C/W
Junction to Ambient (b)(d)	$R_{\theta JA}$	100	°C/W
Junction to Ambient (a)(e)	$R_{\theta JA}$	120	°C/W

### NOTES:

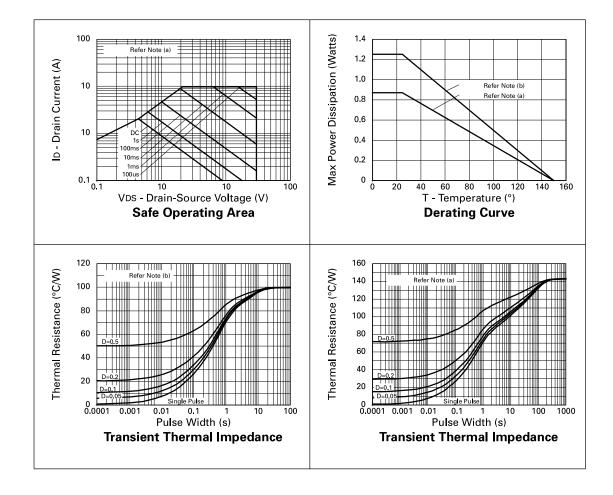
- (a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions
- (b) For a device surface mounted on FR4 PCB measured at t≤10 secs.
- (c) Repetitive rating pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.
- (d) For device with one active die.
- (e) For device with two active die running at equal power.



### **N-CHANNEL CHARACTERISTICS**



### **P-CHANNEL CHARACTERISTICS**





N-CHANNEL ELECTRICAL CHARACTERISTICS (at  $T_{amb} = 25^{\circ}C$  unless otherwise stated).

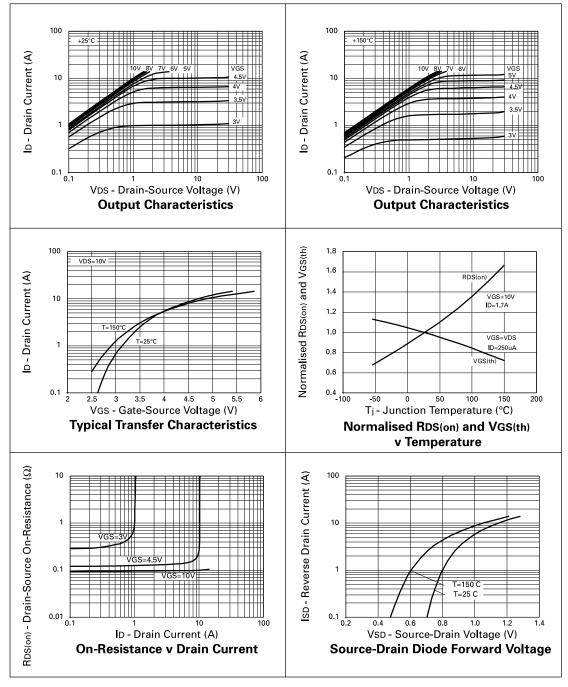
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS	
STATIC							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	30			V	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			1	μА	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	
Gate-Body Leakage	I <sub>GSS</sub>			100	nA	$V_{GS}$ = $\pm$ 20V, $V_{DS}$ =0V	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	1.0			V	$I_D = 250 \mu A$ , $V_{DS} = V_{GS}$	
Static Drain-Source On-State Resistance (1)	R <sub>DS(on)</sub>			0.135 0.200	Ω Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =1.7A V <sub>GS</sub> =4.5V, I <sub>D</sub> =0.85A	
Forward Transconductance (3)	g <sub>fs</sub>	1.9			s	V <sub>DS</sub> =10V,I <sub>D</sub> =0.85A	
DYNAMIC (3)							
Input Capacitance	C <sub>iss</sub>		290		pF	V 05 V V 0V	
Output Capacitance	C <sub>oss</sub>		70		pF	V <sub>DS</sub> =25 V, V <sub>GS</sub> =0V, f=1MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>		20		pF		
SWITCHING(2) (3)			•	•			
Turn-On Delay Time	t <sub>d(on)</sub>		2.5		ns		
Rise Time	t <sub>r</sub>		4.1		ns	V <sub>DD</sub> =15V, I <sub>D</sub> =1.7A R <sub>G</sub> =6.1Ω, R <sub>D</sub> =8.7Ω	
Turn-Off Delay Time	t <sub>d(off)</sub>		9.6		ns	R <sub>G</sub> =6.1Ω, R <sub>D</sub> =8.7Ω (Refer to test circuit)	
Fall Time	t <sub>f</sub>		4.4		ns		
Total Gate Charge	$Q_g$			8	nC	V <sub>DS</sub> =24V,V <sub>GS</sub> =10V, I <sub>D</sub> =1.7A (Refer to test circuit	
Gate-Source Charge	$Q_{gs}$			1.2	nC		
Gate Drain Charge	$Q_{gd}$			2	nC		
SOURCE-DRAIN DIODE	-					-	
Diode Forward Voltage (1)	V <sub>SD</sub>			0.95	V	T <sub>j</sub> =25°C, I <sub>S</sub> =1.7A, V <sub>GS</sub> =0V	
Reverse Recovery Time (3)	t <sub>rr</sub>		16.9		ns	T <sub>j</sub> =25°C, I <sub>F</sub> =1.7A,	
Reverse Recovery Charge(3)	$Q_{rr}$		9.5		nC	di/dt= 100A/μs	

#### NOTES:

- (1) Measured under pulsed conditions. Width=300 $\mu s.$  Duty cycle  ${\leq}2\%.$
- (2) Switching characteristics are independent of operating junction temperature.
- (3) For design aid only, not subject to production testing.



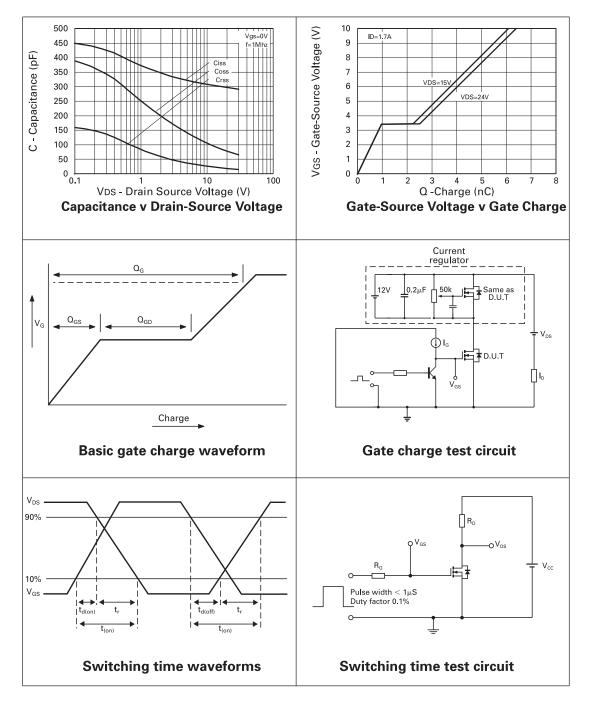
### **N-CHANNEL TYPICAL CHARACTERISTICS**



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### **N-CHANNEL CHARACTERISTICS**





P-CHANNEL ELECTRICAL CHARACTERISTICS (at  $T_{amb}$  = 25°C unless otherwise stated).

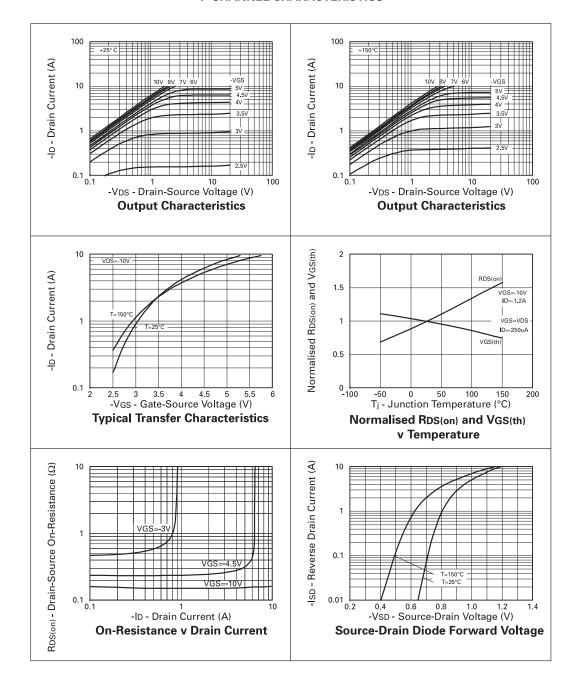
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS	
STATIC			•			•	
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	-30			٧	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			-1	μА	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V	
Gate-Body Leakage	I <sub>GSS</sub>			±100	nA	$V_{GS}$ = $\pm 20V$ , $V_{DS}$ = $0V$	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	-1.0			٧	$I_D = -250 \mu A, V_{DS} = V_{GS}$	
Static Drain-Source On-State Resistance (1)	R <sub>DS(on)</sub>			0.185 0.27	Ω	V <sub>GS</sub> =-10V, I <sub>D</sub> =-1.2A V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-0.6A	
Forward Transconductance (3)	g <sub>fs</sub>	0.92			S	V <sub>DS</sub> =-10V,I <sub>D</sub> =-0.6A	
DYNAMIC (3)							
Input Capacitance	C <sub>iss</sub>		270		pF	V 05 V V 0V	
Output Capacitance	Coss		80		pF	V <sub>DS</sub> =-25 V, V <sub>GS</sub> =0V, f=1MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>		30		pF		
SWITCHING(2) (3)							
Turn-On Delay Time	t <sub>d(on)</sub>		2.6		ns		
Rise Time	t <sub>r</sub>		4.8		ns	V <sub>DD</sub> =-15V, I <sub>D</sub> =-1.2A	
Turn-Off Delay Time	t <sub>d(off)</sub>		13.1		ns	$R_G=6.2\Omega$ , $R_D=6.2\Omega$ (Refer to test circuit)	
Fall Time	t <sub>f</sub>		9.3		ns	(Neier to test circuit)	
Total Gate Charge	$Q_g$			7	nC	., .,,,,,	
Gate-Source Charge	Q <sub>gs</sub>			1.2	nC	V <sub>DS</sub> =-24V,V <sub>GS</sub> =-10V, I <sub>D</sub> =-1.2A (Refer to test circuit	
Gate Drain Charge	$Q_{gd}$			2	nC		
SOURCE-DRAIN DIODE							
Diode Forward Voltage (1)	V <sub>SD</sub>			-0.95	٧	T <sub>j</sub> =25°C, I <sub>S</sub> =-1.2A, V <sub>GS</sub> =0V	
Reverse Recovery Time (3)	t <sub>rr</sub>		21.4		ns	T <sub>j</sub> =25°C, I <sub>F</sub> =-1.2A, di/dt= 100A/μs	
Reverse Recovery Charge(3)	O <sub>rr</sub>		15.7		nC		

#### NOTES:

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- (2) Switching characteristics are independent of operating junction temperature.
- (3) For design aid only, not subject to production testing.

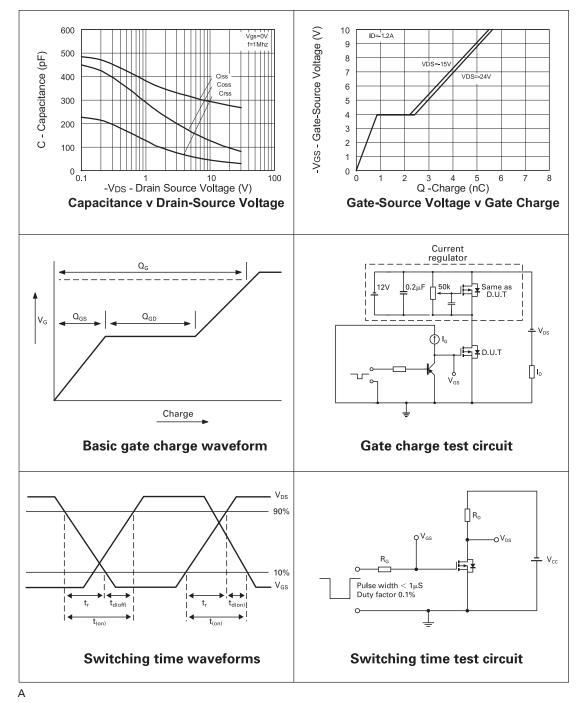


### **P-CHANNEL CHARACTERISTICS**





### P-CHANNEL TYPICAL CHARACTERISTICS



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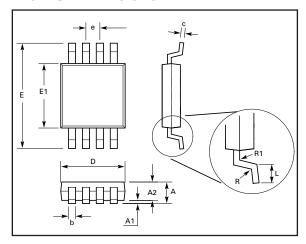
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0.023

### **PACKAGE DIMENSIONS**



. , , , , , , , , , , , , , , , , , , ,	OT DETAILS	
1.02		
	4.8 0.189	
0.41 0.016 →	0.65	mm inches

PAD LAYOUT DETAILS

DIM	Millimeters		Inches		
	Min.	Max.	Min.	Max.	
Α	-	1.10	-	0.0433	
A1	0.05	0.15	0.002	0.006	
A2	0.75	0.95	0.0295	0.0374	
b	0.25	0.40	0.010	0.0157	
С	0.13	0.23	0.005	0.009	
D	2.90	3.10	0.114	0.122	
Е	4.90	BSC	0.193 BSC		
E1	2.90	3.10	0.114	0.122	
е	0.65 BSC		0.025 BSC		
L	0.40	0.70	0.0157	0.0192	
R	0.07	-	0.0027	-	
R1	0.07	-	0.0027 -		

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